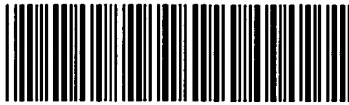


Search Notes



Application/Control No.

09/770,599

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

MILLER ET AL.

Art Unit

3629

SEARCHED

[illegible]

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES
(INCLUDING SEARCH STRATEGY)

		DATE	EXMR
I	US	7/05	DN
	1. PG 2. Patent		
II	FOREIGN		
	1. JPO 2. EPO 3. Derwent		
III	NPL		
	FFext1 FFext2 FFext		